## Development of CMOS pixel sensors for an ILC vertex detector



## Jérôme Baudot, IPHC on behalf of the collaboration:



#### A dedicated design

Inner & outer sensors

#### Current prototypes

- Generic architecture for granular, fast pixels
- Assessment of radiation tolerance
- Integration studies
- Next steps for DBD 2012
  - Benefits of smaller feature size
  - final sensor architectures
- Developments not directly related to DBD
  - First CMOS pixel sensor vertex detector for HEP
  - New technologies for improved performances



# A dedicated design

#### The inner double-sided layer

- Granularity pointing resolution  $\sigma_{s,p} \leq 3 \mu m$
- Separate spatial resolution & time resolution on each layer

#### The two outer double-sided layers

- "Reduced" readout speed Power dissipation
- Lower #pixels but good charge estimation/pixel

### Other constraints

- Material budget  $\leq$  0.16 % X0 / layer
- Radiation tolerance







# A generic achitecture

#### Speed = sparsification

- Include CDS (correlated double sampling) in pixel
- Discriminate pixel output
- Suppress zeros
  - ⇒ column parallel binary output
- → Very few rows powered at a time
  → Low power dissipation



### Spatial resol. (inner layer, side 1)

- Pixel pitch 16x16 µm<sup>2</sup>, binary output
- 1.9 cm<sup>2</sup> of sensitive area
  2x320 rows of 1152 columns
- Two-sided readout @ clock(100MHz)
- $\sigma_{s,p} \leq 3 \mu m$ , integration time  $\leq 50 \mu s$
- Time resol. (inner layer, side 2)
  - Pixel pitch 16x64-80 µm<sup>2</sup>, binary output
  - 1.9 cm<sup>2</sup> of sensitive area
    160 rows of 1152 columns
  - Single-sided readout
  - →  $\sigma_{s.p.} \sim O(5)$  µm, integration time  $\leq 10$  µs
- For power dissipation (outer layers)
  - Pixel pitch 35x35 µm<sup>2</sup>, 4-bits ADC output
  - 4 cm<sup>2</sup> of sensitive area
    576 rows of 576 columns
  - →  $\sigma_{s.p.}$  ~ 4 µm, integration time  $\leq$  100 µs



Analog outputs

# **Generic architecture validation**

#### Full size : MIMOSA 26 (EUDET final sensor)

- Process AMS 0.35 µm OPTO
- Fabricated end 2008 and thinned down to 120 µm
- Yield from 80 to 90% depending on quality required



300 um

# **Radiation tolerance improvement**

#### For a better charge collection

- Standard process epitaxial layer
  - resistivity ~10 Ohm.cm → charges drift ONLY thermally
- Low-doped epitaxial layer
  - resistivity  $\gg$  100 Ohm.cm "HR" grade  $\rightarrow$  deeper depletion
  - Note: depletion level depends on diode voltage
- **Expected shorter collection time** & charges more spatially focused

### Prototype: MIMOSA 26-A<u>HR</u>

- Process AMS 0.35 µm OPTO with 400 Ohm.cm epi. layer
- Exact same layout / MIMOSA 26
- Fabricated in 2009 with 3 composite epi.: 10, 15 & 20 µm thick
- Yield at least as good as std. Epi. Layer
- Test in lab with Ru source (MIP-like  $\beta$ ) S/N x 1.5 to 2 from std to HR epi. (depending on epi. thickness)



Irradiated sensors at



# **MIMOSA 26 performances**



#### **120 GeV** $\pi^-$ beam tests

- With High Resistivity layer
- With typical threshold ~6 x noise: Effi ~ 99.5 %, fake ~ 10<sup>-5</sup> hits/pixel,  $\sigma_{s.p.}$  ~ 3.5 µm
- Readout speed with 80 MHz clock: 115 µs
- Performances checked to hold up to 10<sup>13</sup> n<sub>ed</sub>/cm<sup>2</sup>

# **Optimized pixel for HR epi. layer**

### MIMOSA 22-AHR = pixels + discri. only

- Process AMS 0.35 µm OPTO with 400 Ohm.cm resistivity
- Digital part: 128 columns x 576 rows Analog part: 8 columns x 576 rows
- Fabricated 2010 with 3 epi: 10, 15 & 20 µm thick
- New pixel designs

20.7 µm

18.4 um

elongated

**Discussed later** 

- Different amplification schemes & diode biasing
- Different pitch 18.4, 20.7 µm & elongated pixels
- Irradiated sensors at
  - 150 kRad or 3., 6.10<sup>12</sup> neq/cm<sup>2</sup>
  - Combined 150 Krad +  $3.10^{12} n_{eq}^{2}/cm^{2}$
- Operation t<sub>r.o.</sub> = 92.5 µs (80 MHz), T=20 °C
- Beam test in late summer 2010 with 120 GeV  $\pi^-$

#### Improvements observed

- Lower fake hit rate achievable @ ~100% efficiency below 1 hit/frame on the full matrix
- Spatial resolution reaches  $3\mu$ m: -0.5  $\mu$ m with same pixel pitch  $2\frac{1}{3}$
- Performances stability with irradiation under study





# **Integration studies**

### The PLUME project (see Ingrid Gregor's talk)

- Double sided ladder (2x6 Mimosa 26) @ 0.3% X0
- Passive cooling: air flow
- Power pulsing
- Collab.: Bristol U., DESY, Oxford U., IPHC
- Several iterations over 2009-2012 (Current proto @ 0.6%X0)
  - Classical "secured" sandwich: separated parts bonded together

#### An "aggressive" alternative: SERWIETE

- Embed an ultra-thin sensor in a custom made flex cable
  - cable+sensor sheet  $\leq$  0.15 % X0
  - "single" operation
- Collab.: IKF-Frankfurt, GSI-Darmstadt, IPHC
- Technology provided by IMEC-Belgium
- First trial with an analog sensor of ~0.5 cm<sup>2</sup> ongoing

#### Other alternative with stitching: all-silicon ladder





MIMOSA 18 embedded on a 50µm kapton, 1µm Cu cable



# Next step 1: final architectures

### Two-sided readout with small pitch sensor

- MIMOSA 29, AMS 0.35 μm OPTO
- Pitch 16x16 µm<sup>2</sup>
- Two-sided readout → 50 µs readout time
- Submission in 2011

## 4-bits digital sensor

- MIMOSA 30, AMS 0.35 μm OPTO
- Several ADC prototypes already studied (low power & area)
- Readout time ≤ 100 µs
- Studies on analog sensor with off-line digitization :  $\sigma_{s.p.} \sim 2 \mu m$  with a 20  $\mu r$
- Submission in 2011

### Elongated pixel sensor

- Already studied with MIMOSA 22 AHR (2010)
- Pitch 18.4 µm x 73.6 µm tested (last week) with 120 GeV π-→ 100 % efficiency,  $\sigma_{s,p} \sim 6$  µm

#### ⇒ large pitch validated

Final version: pitch 16 μm x 64 to 80 μm for t<sub>ro.</sub> ~ 10 μs

CMOS pixel sensors for ILC-VXD, IWLC Oct. 2010







# Next step 2: bigger systems

## Within the AIDA FP7 project (2011-2014)

#### Large Area Telescope

- Provide a facility for beam test with 5x5 cm<sup>2</sup> sensitive area
- Produce stitched sensors (could be interesting for ladder integration)
- Operation of final architecture sensors (inner layer)



#### Alignment Investigation Device: AID box

- Performance assessment of double ladders in "real" environment
  - Power pulsing operation
  - Air cooling
- Alignment strategy development
- Use PLUME ladders





#### Motivations for Very Deep Sub-Micrometer processes

- → Higher number of metal layers + smaller feature size → Smaller insensitive area
- ✓ Lower line capacitance → Higher clock freq. (+15 to 20%) → increased readout speed
- Thinner gate oxyde → Higher ionizing radiation

#### **2010**

- Design analog sensor MIMOSA 27 in XFAB 0.18 µm OPTO
  - 16.4 kPixels over 10 mm<sup>2</sup> with 16 different pixel options

#### **2011 & 2012**

- In-beam tests of MIMOSA 27
- Design of building blocks for column // binary readout
  - In-pixel CDS matrix + discriminator
  - Zero suppression logic and readout memomries

#### **2013**

Submission of full size, complete functionalities, prototype



## **Non-DBD** activities

#### The first vertex detector with CMOS sensor

- STAR @ RHIC: heavy ion collisions
- With LBNL
- ULTIMATE sensor ~2x2 cm<sup>2</sup> @ t<sub>r.o.</sub> ~ 200 μs based on MIMOSA 26
- Single material budget ~0.37 % X0
- Submission 2010, physics by 2013
- Other VXD following (CBM@SIS, ALICE@LHC, ...)





#### Exploiting the full CMOS technological potential

- → 3D integration technologies → 1 functionality per tier
- From "standard" CMOS pixel (granular, thin & fast)
  To "intelligent sensors" (granular, thin, ultra-fast, ultra-rad.tol.)
- Targets: ILC 1TeV, CLIC (5-10 ns)
- CAIRN series, started in 2009 within international HEP consortium



### NOW

- Fast binary architecture validated on full scale sensor
- →  $t_{r.o.}$  = 85 µs (for 576 rows),  $\sigma_{s.p.}$  ~ 3 µm @ 18.4 µm pitch
- $\Rightarrow$  299.5 % efficiency for  $\leq$  10<sup>-6</sup> fake hit/pixel @ 3.10<sup>12</sup> n<sub>eq</sub>/cm<sup>2</sup> + 150 kRad

#### ILD-DBD 2012

- Prototypes for each layer validated
- 16x16 μm<sup>2</sup> @ 50 μs / 16x64 μm<sup>2</sup> @ 10 μs / 16x16 μm<sup>2</sup> + 4bits-ADC
- Ladder demonstrator at ~0.3 % X0

#### Besides ILD-DBD

- From 2012: real physics with CMOS pixels (c-tagging, ...)
- 3D sensors
  - Road to CLIC requirements
- Large surface with large pitch
  - Road to larger tracker



## **BACKUPs**



# MAPS, the basics

### Technology

- Industry standard for ICs
- All processes not optimized
  - Epitaxial layer thickness
  - # metal layers
  - Nwell Psubstrate junction



### Intrinsically thin sensors

- sensitive layer ~10-20 μm
  - Small MIP signal, few 100 e- per pixel → requires low pixel noise O(10 e-)
- Substrate almost useless
  - Few μm enough, total thickness could reach 20 μm
- Monolithic & active
  - No external IC required in vicinity



# **MAPS, standard performances**

#### From the MIMOSA family

- Developed at IPHC-Strasbourg
- AMS 0.35 µm process, ~11 µm epitaxial layer
- 3 transistors pixel <u>Sequential analogue readout</u>
- Performances assessed also @ 50 µm thickness
  - Thinning routinely achieve by industry

### Hit rate

- With parallel analog outputs
- 1Mpixels ~ 1ms r.o, time

### Radiation tolerance

- Ionizing: ~Mrad
- Non-ionizing: few 10<sup>12</sup> n<sub>ed</sub>/cm<sup>2</sup>
- Integration time and temperature dependent





# Vertex detector figures of merit







Parameters driving

#### the readout time of a single row

- Clock frequency
- Duration of each control signal, the latter is impacted by
  - Column length
  - Process feature size





#### Beam test setup

- 2009 & 2010 campaigns at CERN SPS with 120 GeV  $\pi$ -
- Using IPHC DAS based on NI-PXI digital IO board  $\rightarrow$  event rate ~ kHz
- Operating at 80 MHz ( $t_{r.o.}$  = 115 µs) and T=20 °C (80 Mbits/s @ output)



#### Thresholding strategy validation







CMOS pixel sensors for ILC-VXD, IWLC Oct. 2010 -

# **Time resolution in rolling-shutter**

